

2N3337 • 2N3338 • 2N3339

NPN RF-IF-AGC AMPLIFIERS

DIFFUSED SILICON PLANAR* TRANSISTORS

GENERAL DESCRIPTION — The 2N3337, 2N3338, and 2N3339 are NPN silicon PLANAR transistors designed specifically for RF-IF-AGC applications. They feature high power gain, low noise, and excellent forward AGC characteristics.

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures

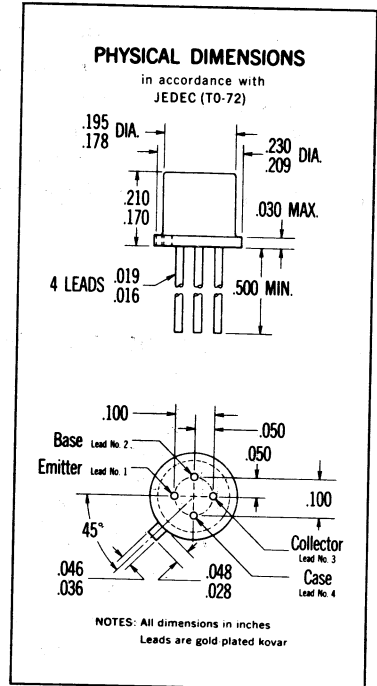
Storage Temperature	-65°C to +200°C
Operating Junction Temperature	200°C Maximum
Lead Temperature (soldering, 60 sec. time limit)	300°C Maximum

Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature (Notes 2 & 3)	0.5 Watt
at 25°C Ambient Temperature (Notes 2 & 3)	0.3 Watt

Maximum Voltages

V_{CBO}	Collector to Base Voltage	40 Volts
V_{CEO}	Collector to Emitter Voltage (Note 4)	40 Volts
V_{EBO}	Emitter to Base Voltage	4.0 Volts



ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

2N3337
2N3338
2N3339

Symbol	Characteristics	Min.	Max.	Min.	Max.	Units	Test Conditions
G_{Pe1}	Small-Signal Power Gain (f = 60 MHz) (Note 7)	24				dB	$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
G_{Pe2}	Small-Signal Power Gain (f = 60 MHz) (Note 7)	-30				dB	See Note 5
G_{Pe1}	Small-Signal Power Gain (f = 200 MHz) (Note 8)			15		dB	$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
G_{Pe2}	Small-Signal Power Gain (f = 200 MHz) (Note 8)			-30		dB	See Note 6
NF	Noise Figure (f = 60 MHz) 2N3338 only (Note 7)		5.5			dB	$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
NF	Noise Figure (f = 200 MHz) (Note 8)				5.5	dB	$I_C = 4.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$

NOTES:

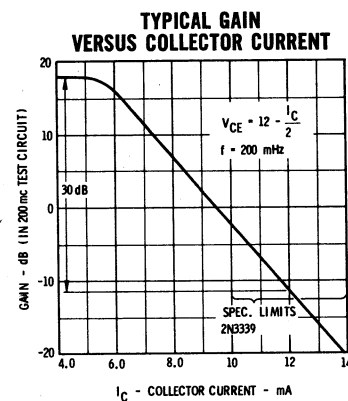
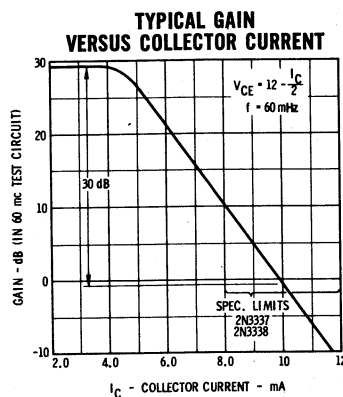
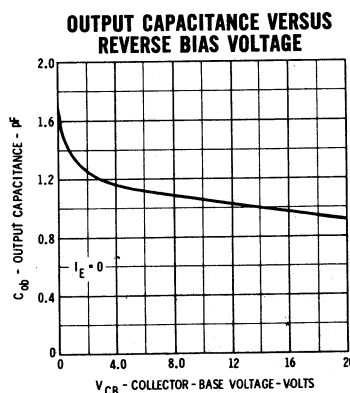
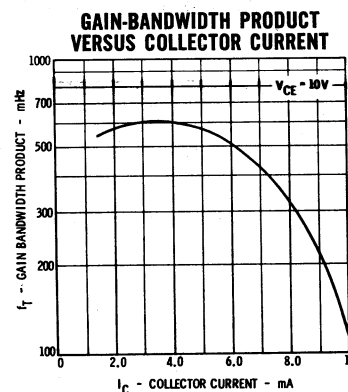
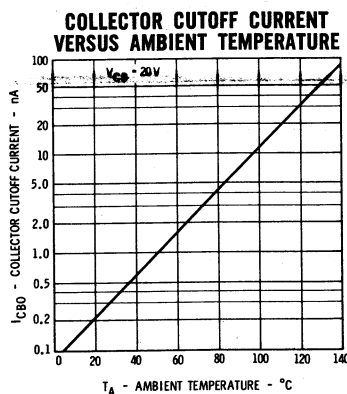
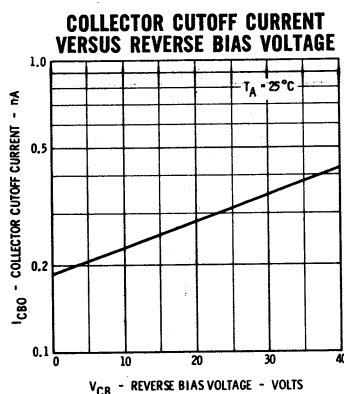
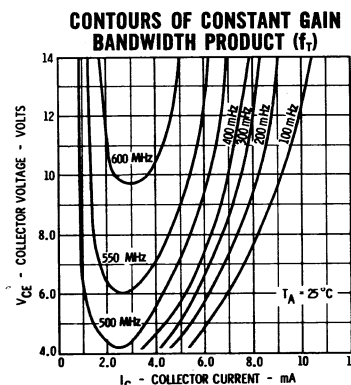
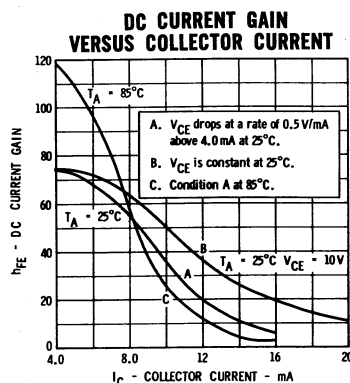
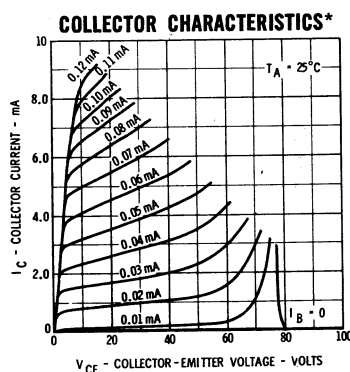
- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- These ratings give a maximum junction temperature of 200°C and junction-to-case thermal resistance of 350°C/Watt (derating factor of 2.86 mW/°C); junction-to-ambient thermal resistance of 583°C/Watt (derating factor of 1.72 mW/°C).
- This rating refers to a high-current point where collector-to-emitter voltage is lowest.
- G_{Pe2} is $\leq G_{Pe1} - 30 \text{ dB}$ when I_C is between 8.0 and 12 mA in the 60 MHz circuit on page 4. $V_{CE} = (12 - \frac{I_C}{2})$.
- G_{Pe2} is $\leq G_{Pe1} - 30 \text{ dB}$ when I_C is between 10 and 14 mA in the 200 MHz circuit on page 4. $V_{CE} = (12 - \frac{I_C}{2})$.
- Bandwidth = 10 MHz Source resistance (as seen by transistor) = 200Ω.
- Bandwidth = 8.0 MHz Source resistance (as seen by transistor) = 100Ω.
- Pulse Conditions: length = 300 μsec; duty cycle = 1%.

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ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

Symbol	Characteristic	Min.	Max.	Units	Test Conditions	
h_{FE}	DC Current Gain	30			$I_C = 4.0 \text{ mA}$	$V_{CE} = 10 \text{ V}$
I_{CBO}	Collector Cutoff Current		25	nA	$I_E = 0$	$V_{CB} = 20 \text{ V}$
$I_{CBO}(125^\circ\text{C})$	Collector Cutoff Current		5.0	μA	$I_E = 0$	$V_{CB} = 20 \text{ V}$
C_{ob}	Output Capacitance		1.6	pf	$I_E = 0$	$V_{CB} = 10 \text{ V}$
h_{fe}	High Frequency Current Gain ($f = 100 \text{ mc}$)	4.0			$I_C = 4.0 \text{ mA}$	$V_{CE} = 10 \text{ V}$
BV_{CBO}	Collector to Base Breakdown Voltage	40		Volts	$I_C = 100 \mu\text{A}$	$I_E = 0$
$V_{CEO(sust)}$	Collector to Emitter Sustaining Voltage (Notes 4 and 9)	40		Volts	$I_C = 3.0 \text{ mA}$ (pulsed)	$I_B = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	4.0		Volts	$I_E = 100 \mu\text{A}$	$I_C = 0$

TYPICAL ELECTRICAL CHARACTERISTICS



* Single family characteristics on Transistor Curve Tracer

TYPICAL SMALL SIGNAL COMMON EMITTER "Y" PARAMETERS

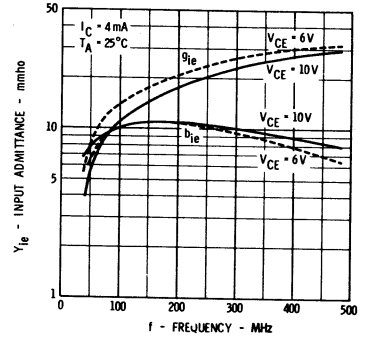
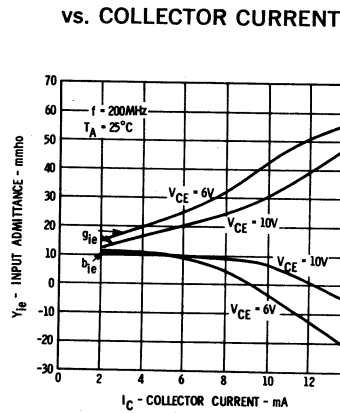
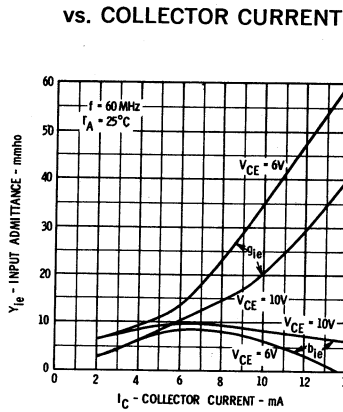
60 MHz

200 MHz

vs. FREQUENCY

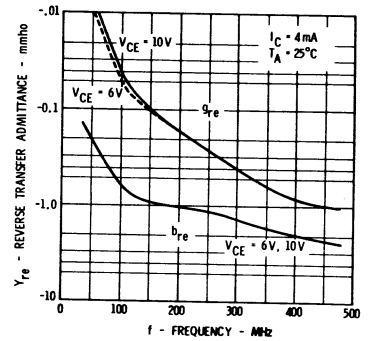
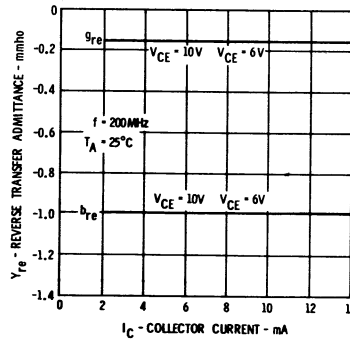
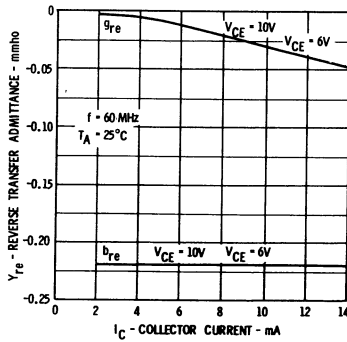
y_{ie}

Input Admittance
(output short circuit)



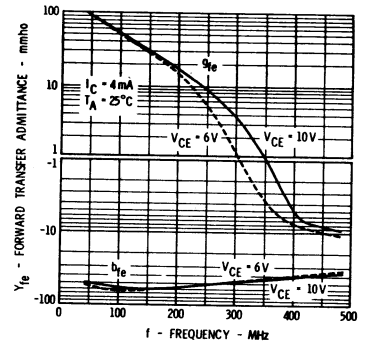
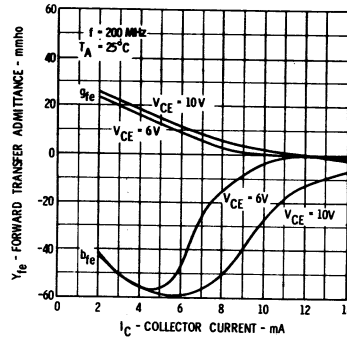
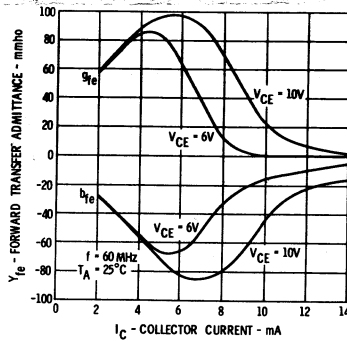
y_{re}

Reverse
Transfer Admittance
(input short circuit)



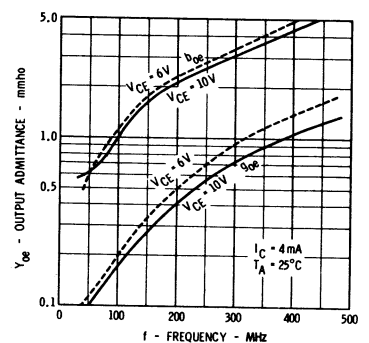
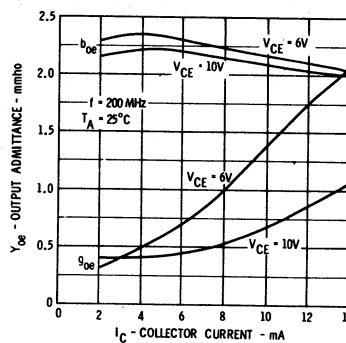
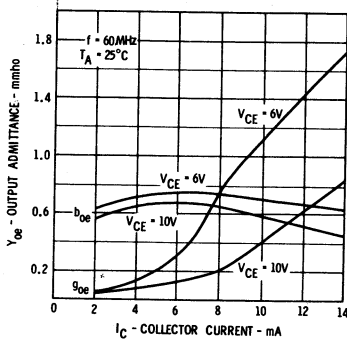
y_{fe}

Forward
Transfer Admittance
(output short circuit)



y_{oe}

Output Admittance
(input short circuit)



2N3426

NPN HIGH-SPEED, HIGH CURRENT, SWITCH

SILICON PLANAR* EPITAXIAL TRANSISTOR

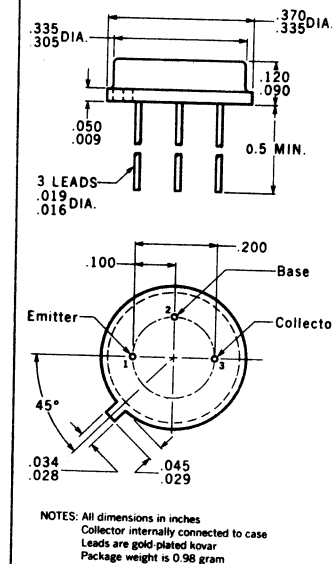
GENERAL DESCRIPTION

The 2N3426 is a silicon PLANAR epitaxial transistor with very high speed switching capability at high currents. A maximum $V_{CE(sat)}$ of 0.7 V at one ampere and minimum f_T of 450 MHz qualify it especially for use as a thin film memory driver.

ABSOLUTE MAXIMUM RATINGS (Note 1)

Maximum Temperatures	
Storage Temperature	-65°C to +200°C
Operating Junction Temperature	200°C Maximum
Lead Temperature (Soldering, 60 sec. time limit)	300°C Maximum
Maximum Power Dissipation	
Total Dissipation at 25°C Case Temperature (Notes 2 and 3)	3.0 Watts
at 25°C Ambient Temperature (Notes 2 and 3)	0.6 Watt
Maximum Voltages and Current	
V_{CBO} Collector to Base Voltage	25 Volts
V_{CEO} Collector to Emitter Voltage (Note 4)	12 Volts
V_{EBO} Emitter to Base Voltage	4.0 Volts
I_C Collector Current	1.0 Amp

PHYSICAL DIMENSIONS



ELECTRICAL CHARACTERISTICS (25°C free air temperature unless otherwise noted)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Conditions
t_{on}	Turn On Time (Note 6)		10	15	ns	$I_C \approx 1000$ mA, $I_{B1} \approx 100$ mA
t_{off}	Turn Off Time (Note 6)		15	25	ns	$I_C \approx 1000$ mA, $I_{B1} \approx 100$ mA, $I_{B2} \approx -100$ mA
τ_s	Charge Storage Time (Note 6)			15	ns	$I_C \approx 100$ mA, $I_{B1} \approx 100$ mA, $I_{B2} \approx -100$ mA
h_{fe}	High Frequency Current Gain ($f = 100$ MHz)	4.5	6.5			$I_C = 100$ mA, $V_{CE} = 5.0$ V
$V_{CE(sat)}$	Collector Saturation Voltage (Note 5)	0.18	0.23		Volts	$I_C = 100$ mA, $I_B = 10$ mA
$V_{CE(sat)}$	Collector Saturation Voltage (Note 5)	0.24	0.33		Volts	$I_C = 300$ mA, $I_B = 30$ mA
$V_{CE(sat)}$	Collector Saturation Voltage (Notes 5 & 7)	0.51	0.7		Volts	$I_C = 1000$ mA, $I_B = 100$ mA
h_{FE}	DC Pulse Current Gain (Note 5)	30	60	120		$I_C = 300$ mA, $V_{CE} = 0.5$ V
C_{obo}	Output Capacitance			25	pF	$V_{CB} = 0$, $I_E = 0$
h_{fe}	High Frequency Current Gain ($f = 100$ MHz)	2.0				$I_C = 500$ mA, $V_{CB} = 0$

NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- These ratings give a maximum junction temperature of 200°C and junction-to-case thermal resistance of 58.3°C/Watt (derating factor of 17.2 mW/°C); junction-to-ambient thermal resistance of 291.6°C/Watt (derating factor of 3.43 mW/°C).
- This rating refers to a high-current point where collector-to-emitter voltage is lowest.
- Pulse Conditions: length = 300 μ s ; duty cycle = 1%.
- See switching circuit for exact values of I_C , I_{B1} , I_{B2} .
- This limit applies for a measurement made 1/4" from the bottom of the case.

*Planar is a patented Fairchild process.

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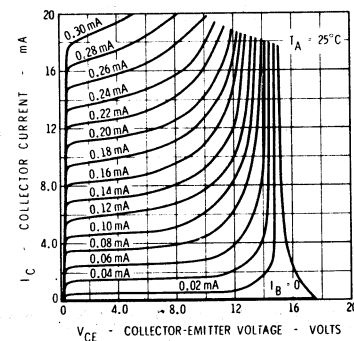
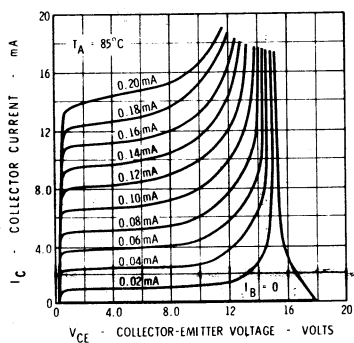
FAIRCHILD TRANSISTOR 2N3426

ELECTRICAL CHARACTERISTICS (25°C free air temperature unless otherwise noted)

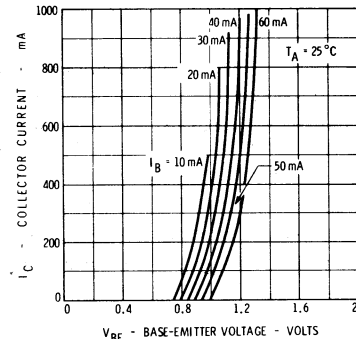
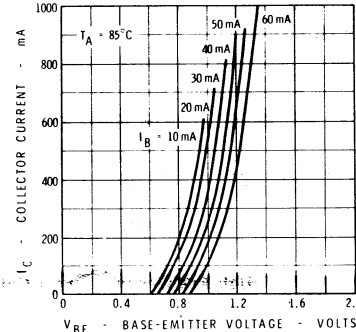
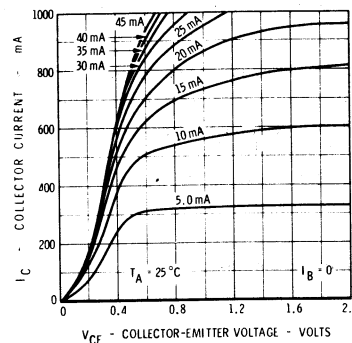
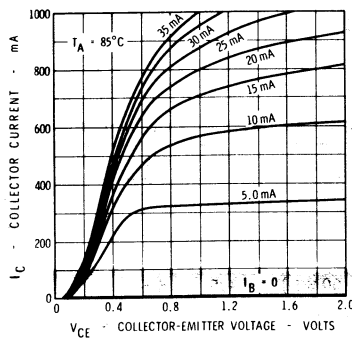
Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Conditions	
$V_{CE(sat)}$	Collector Saturation Voltage		0.17	0.25	Volts	$I_C = 10$ mA	$I_B = 1.0$ mA
$V_{CE(sat)} (85^\circ\text{C})$	Collector Saturation Voltage (Note 5)		0.25	0.5	Volts	$I_C = 300$ mA	$I_B = 30$ mA
$V_{BE(sat)}$	Base Saturation Voltage		0.68	0.78	Volts	$I_C = 10$ mA	$I_B = 1.0$ mA
$V_{BE(sat)}$	Base Saturation Voltage (Note 5)		0.84	1.1	Volts	$I_C = 100$ mA	$I_B = 10$ mA
$V_{BE(sat)}$	Base Saturation Voltage (Note 5)		1.0	1.3	Volts	$I_C = 300$ mA	$I_B = 30$ mA
$V_{BE(sat)}$	Base Saturation Voltage (Note 5)	0.9	1.36	2.1	Volts	$I_C = 1000$ mA	$I_B = 100$ mA
I_{CES}	Collector Reverse Current		1.5	100	μA	$V_{CE} = 15$ V	$V_{EB} = 0$
C_{obo}	Output Capacitance		6.2	15	pF	$I_E = 0$	$V_{CB} = 5.0$ V
C_{ibo}	Input Capacitance		14.8	25	pF	$I_C = 0$	$V_{EB} = 0.5$ V
BV_{CBO}	Collector to Base Breakdown Voltage	25			Volts	$I_C = 500$ μA	$I_E = 0$
$V_{CEO(sust)}$	Collector to Emitter Sustaining Voltage (Notes 4 and 5)	12			Volts	$I_C = 30$ mA	$I_B = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	4.0			Volts	$I_E = 100$ μA	$I_C = 0$
h_{FE}	DC Pulse Current Gain (Note 5)	30	50			$I_C = 100$ mA	$V_{CE} = 0.5$ V
h_{FE}	DC Pulse Current Gain (Note 5)	20	45			$I_C = 10$ mA	$V_{CE} = 0.5$ V

TYPICAL COLLECTOR AND BASE CHARACTERISTICS *

ACTIVE REGION



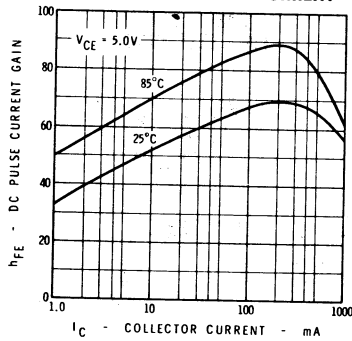
SATURATION REGION



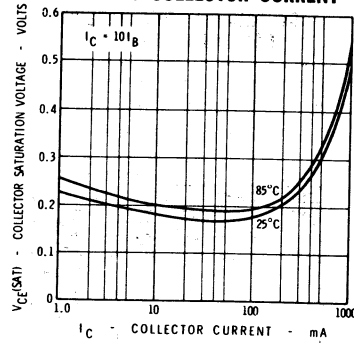
FAIRCHILD TRANSISTOR 2N3426

TYPICAL ELECTRICAL CHARACTERISTICS

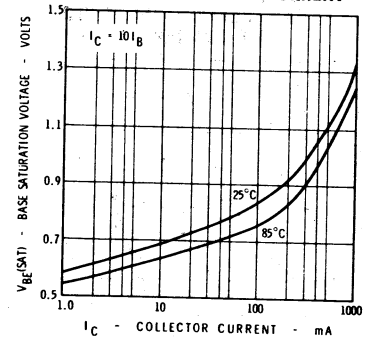
**DC PULSE CURRENT GAIN
VERSUS COLLECTOR CURRENT**



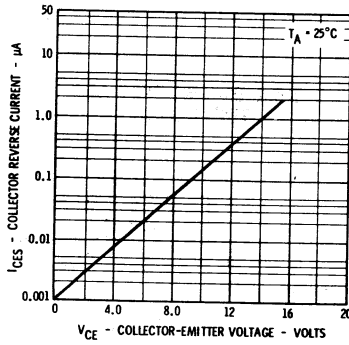
**COLLECTOR SATURATION VOLTAGE
VERSUS COLLECTOR CURRENT**



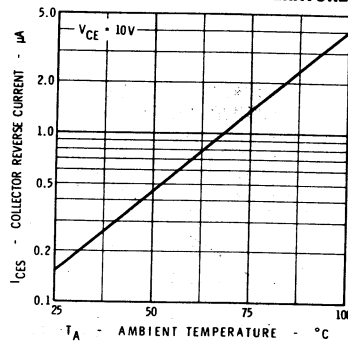
**BASE SATURATION VOLTAGE
VERSUS COLLECTOR CURRENT**



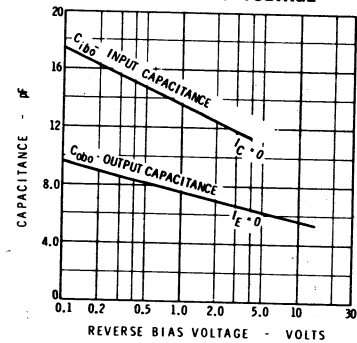
**COLLECTOR REVERSE CURRENT
VERSUS REVERSE BIAS VOLTAGE**



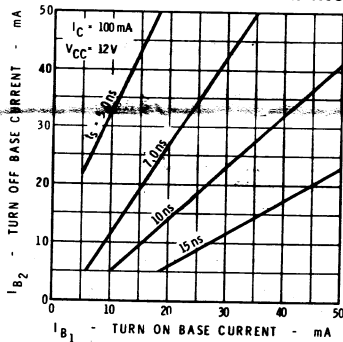
**COLLECTOR REVERSE CURRENT
VERSUS AMBIENT TEMPERATURE**



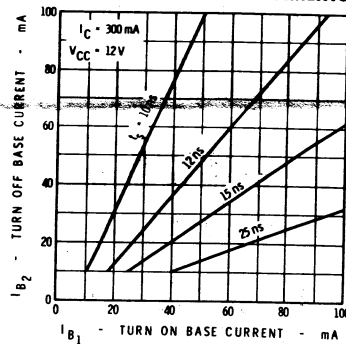
**INPUT AND OUTPUT
CAPACITANCES VERSUS
REVERSE BIAS VOLTAGE**



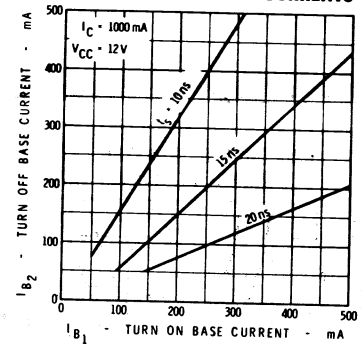
**STORAGE TIME VERSUS TURN ON
AND TURN OFF BASE CURRENTS**



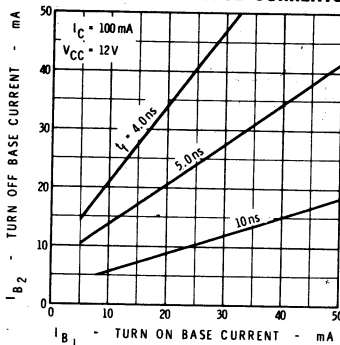
**STORAGE TIME VERSUS TURN ON
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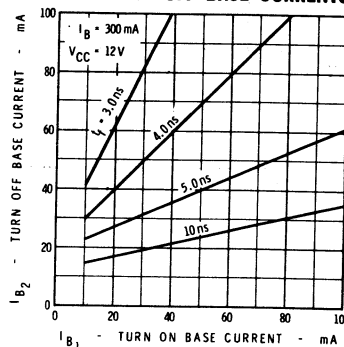
**STORAGE TIME VERSUS TURN ON
AND TURN OFF BASE CURRENTS**



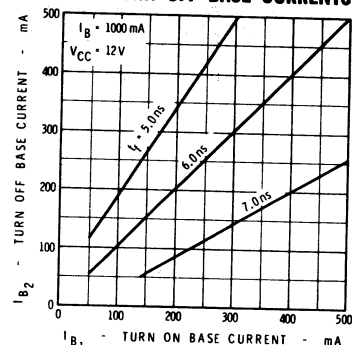
**FALL TIME VERSUS TURN ON
AND TURN OFF BASE CURRENTS**



**FALL TIME VERSUS TURN ON
AND TURN OFF BASE CURRENTS**



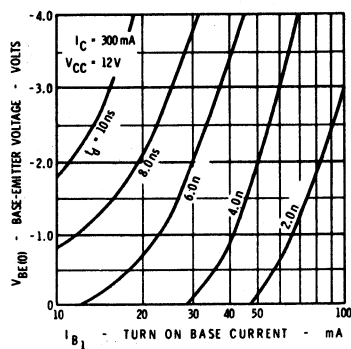
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AND TURN OFF BASE CURRENTS**



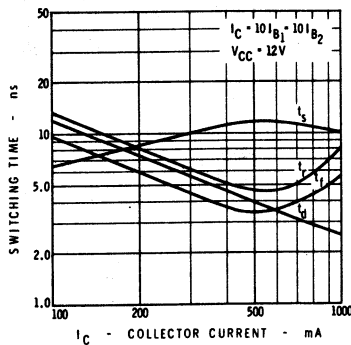
FAIRCHILD TRANSISTOR 2N3426

TYPICAL ELECTRICAL CHARACTERISTICS

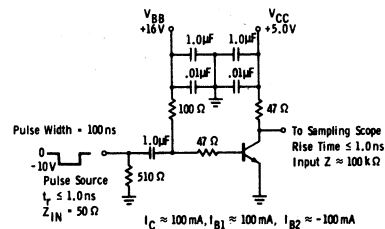
DELAY TIME VERSUS TURN ON BASE CURRENT AND REVERSE BASE-EMITTER VOLTAGE



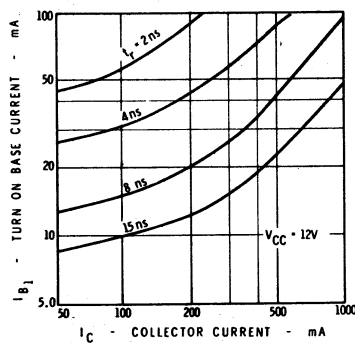
SWITCHING TIMES VERSUS COLLECTOR CURRENT



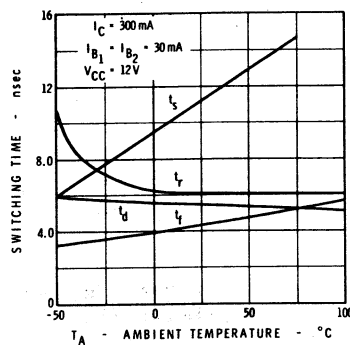
CHARGE STORAGE TIME TEST CIRCUIT



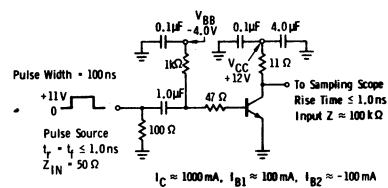
RISE TIME VERSUS COLLECTOR AND TURN ON BASE CURRENTS



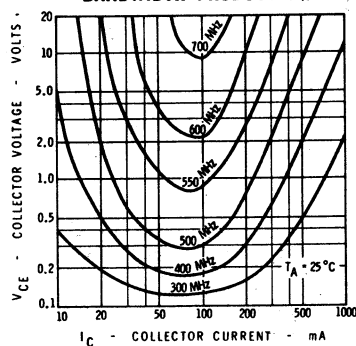
SWITCHING TIMES VERSUS AMBIENT TEMPERATURE



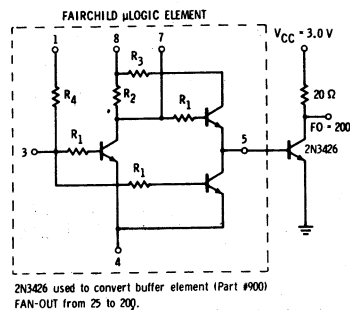
TURN ON AND TURN OFF TEST CIRCUIT



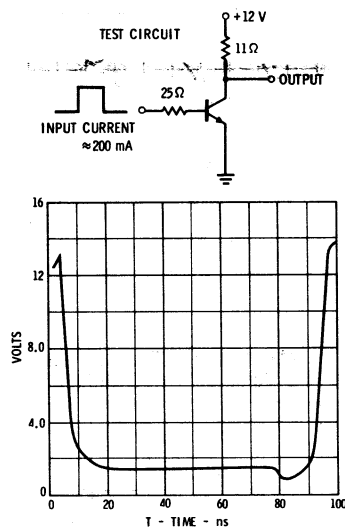
CONTOURS OF CONSTANT GAIN BANDWIDTH PRODUCT (f_T)



IMPROVING FAN-OUT CAPABILITY



HIGH SPEED 1 AMPERE PULSE SOURCE



2N3563

NPN LOW LEVEL RF AMPLIFIER

DIFFUSED SILICON PLANAR EPITAXIAL TRANSISTOR

The 2N3563 is an NPN silicon PLANAR epitaxial transistor designed for low-level RF applications. It features high power gain, low noise and low leakage in a new solid package designed to give maximum mechanical support to the transistor chip.

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures

Operating Junction Temperature	+125°C Maximum
Storage Temperature	-55°C to +125°C
Soldering Temperature (10 sec. time limit)	+260°C Maximum

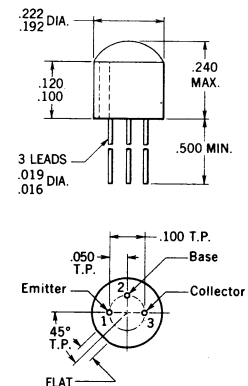
Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature	(Note 2)	0.5 Watt
at 65°C Case Temperature	(Note 2)	0.3 Watt
at 25°C Ambient Temperature	(Note 2)	0.2 Watt

Maximum Voltages

V_{CBO}	Collector to Base Voltage	30 Volts
V_{CEO}	Collector to Emitter Voltage	(Note 3) 12 Volts
V_{EBO}	Emitter to Base Voltage	2.0 Volts

PHYSICAL DIMENSIONS Epoxy package TO-106



NOTES: All dimensions in inches.
All leads electrically isolated from case.
Package weight is 0.31 gram. Package
is electrically non-conductive material.

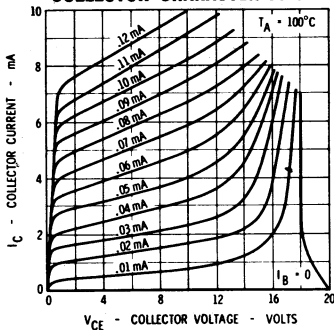
ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

Symbol	Characteristics	Min.	Typ.	Max.	Units	Test Conditions
h_{FE}	DC Pulse Current Gain (Note 4)	20	50	200		$I_C = 8.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
$V_{CE(sat)}$	Collector Saturation Voltage		0.1		Volts	$I_C = 10 \text{ mA}$ $I_B = 1.0 \text{ mA}$
C_{obo}	Open Circuit Output Capacitance		1.3	1.7	pf	$I_E = 0$ $V_{CB} = 10 \text{ V}$
C_{cb}	Collector-base Transfer (Note 7)		0.8		pf	$I_E = 0$ $V_{CB} = 10 \text{ V}$
I_{CBO}	Collector Cutoff Current			50	nA	$I_E = 0$ $V_{CB} = 15 \text{ V}$
$I_{CBO(65^\circ C)}$	Collector Cutoff Current			5.3	μA	$I_E = 0$ $V_{CB} = 15 \text{ V}$
h_{fe}	High Frequency Current Gain ($f = 100 \text{ mc}$)	6.0	9.0			$I_C = 8.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
G_{pe}	Available Power Gain (neutralized) (Note 5) ($f = 200 \text{ mc}$)	14	17		db	$I_C = 8.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
NF	Noise Figure (Note 6)		4.0		db	$I_C = 1.0 \text{ mA}$ $V_{CE} = 6.0 \text{ V}$
$r_b'C_c$	Collector-Base Time Constant ($f = 79.8 \text{ mc}$)	8.0	15	25	psec	$I_C = 8.0 \text{ mA}$ $V_{CB} = 10 \text{ V}$
h_{fe}	Small Signal Current Gain ($f = 1.0 \text{ Kc}$)	20		250		$I_C = 8.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
BV_{CBO}	Collector to Base Breakdown Voltage	30			Volts	$I_E = 0$ $I_C = 100 \mu A$
$V_{CEO(sust)}$	Collector to Emitter Sustaining Voltage (Notes 3 and 4)	12			Volts	$I_C = 3.0 \text{ mA}$ (pulsed) $I_B = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	2.0			Volts	$I_C = 0$ $I_E = 10 \mu A$

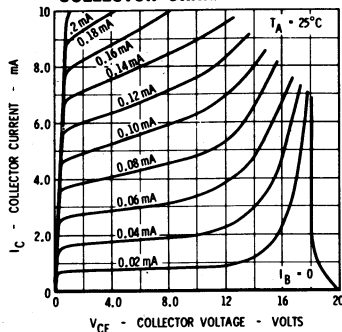
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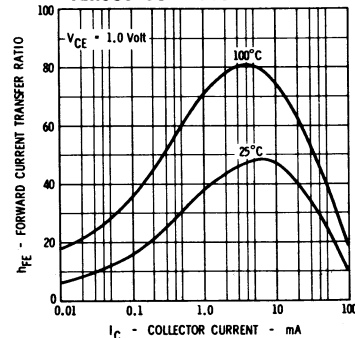
COLLECTOR CHARACTERISTICS*



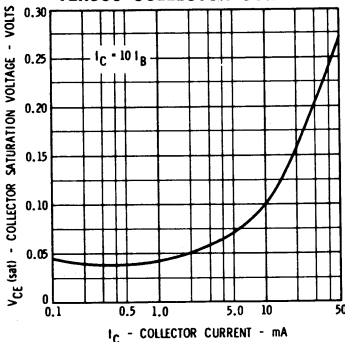
COLLECTOR CHARACTERISTICS*



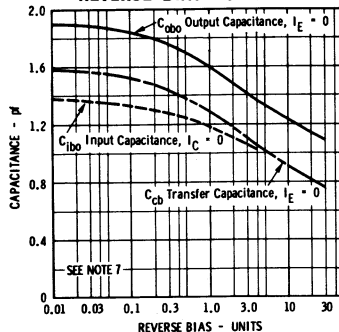
**PULSED DC CURRENT GAIN
VERSUS COLLECTOR CURRENT**



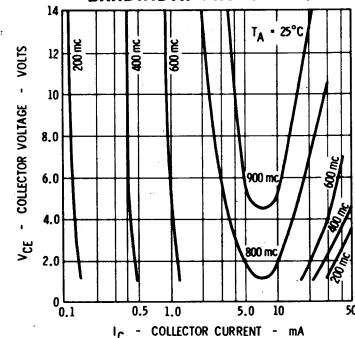
**COLLECTOR SATURATION VOLTAGE
VERSUS COLLECTOR CURRENT**



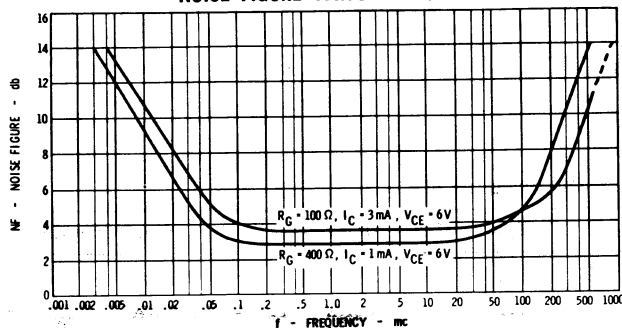
**CAPACITANCE VERSUS
REVERSE BIAS VOLTAGE**



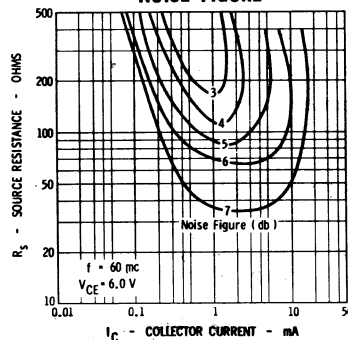
**CONTOURS OF CONSTANT
BANDWIDTH PRODUCT (f_T)**



NOISE FIGURE VERSUS FREQUENCY

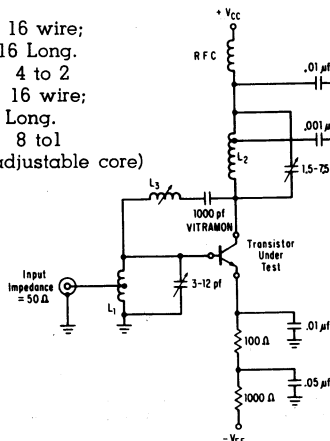


**CONTOURS OF CONSTANT
NOISE FIGURE**



NEUTRALIZED 200 MC POWER GAIN AMPLIFIER TEST CIRCUIT

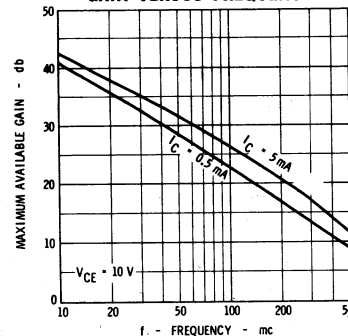
- L₁ — 3.5 Turns No. 16 wire;
5/16 Dia; 7/16 Long.
Turns Ratio 4 to 2
- L₂ — 8.0 Turns No. 16 wire;
1/8 Dia; 7/8 Long.
Turns Ratio 8 to 1
- L₃ — 0.4-0.65 μh (adjustable core)



NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These ratings give a maximum junction temperature of 125°C and junction-to-case thermal resistance of 200°C/Watt (derating factor of 5.0 mW/°C); junction-to-ambient thermal resistance of 500°C/Watt (derating factor of 2.0 mW/°C).
- (3) Rating refers to a high-current point where collector-to-emitter voltage is lowest.
- (4) Pulse Conditions: length = 300 μsec; duty cycle ≤ 1%.
- (5) Forward gain (db) + reverse gain (db) < (-20 db). See test circuit.
- (6) f = 60 mc; R_S = 400 Ω.
- (7) C_{cb} is measured using a three-terminal measurement technique with case and emitter guarded. C_{cb} is equivalent to C_{re}.

**MAXIMUM AVAILABLE
GAIN VERSUS FREQUENCY**



* Single family characteristics on Transistor Curve Tracer.

2N3564

NPN RF AMPLIFIER

DIFFUSED SILICON PLANAR* EPITAXIAL TRANSISTOR

GENERAL DESCRIPTION - The 2N3564 is an NPN silicon PLANAR Epitaxial Transistor. It is designed for high-frequency wide-band amplifiers and is useful in low-power, small-signal tuned RF and IF applications. This device is similar to the SE 1010.

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures

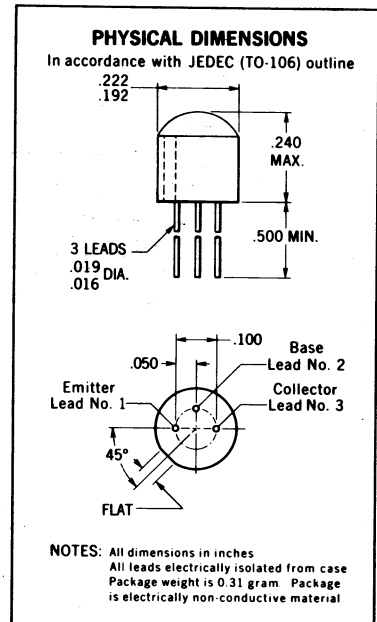
Storage Temperature	-55°C to +125°C
Operating Junction Temperature	+125°C Maximum
Lead Temperature (Soldering, 10 sec. time limit)	+260°C Maximum

Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature	(Note 2)	0.5 Watt
at 65°C Case Temperature	(Note 2)	0.3 Watt
at 25°C Ambient Temperature	(Note 2)	0.2 Watt

Maximum Voltages

V_{CBO}	Collector to Base Voltage	30 Volts
V_{CEO}	Collector to Emitter Voltage (Note 3)	15 Volts
V_{EBO}	Emitter to Base Voltage	4.0 Volts



ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

Symbol	Characteristics	Min.	Typ.	Max.	Units	Test Conditions
BV_{CBO}	Collector to Base Breakdown Voltage	30			Volts	$I_C = 100 \mu A$, $I_E = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	4.0			Volts	$I_C = 100 \mu A$, $I_B = 0$
$BV_{CEO(sust)}$	Collector to Emitter Sustaining Voltage (Notes 3 & 4)	15			Volts	$I_C = 10 mA$, $I_B = 0$
$V_{CE(sat)}$	Collector Saturation Voltage			0.3	Volts	$I_C = 20 mA$, $I_B = 2.0 mA$
$V_{BE(sat)}$	Base Saturation Voltage			0.97	Volts	$I_C = 20 mA$, $I_B = 2.0 mA$
I_{CBO}	Collector Cutoff Current			50	nA	$V_{CB} = 15 V$, $I_E = 0$
h_{FE}	DC Pulse Current Gain (Note 4)	20	70			$I_C = 15 mA$, $V_{CE} = 10 V$
h_{fe}	Low Frequency Current Gain (f = 1 kHz)	20	80			$I_C = 15 mA$, $V_{CE} = 10 V$
h_{fe}	High Frequency Current Gain (f = 100 MHz)	4.0	7.5			$I_C = 15 mA$, $V_{CE} = 10 V$
r_b	Real Part of h_{ie} (f = 350 MHz)		30		ohms	$I_C = 15 mA$, $V_{CE} = 10 V$
C_{obo}	Open Circuit Output Capacitance	2.5	3.5		pF	$V_{CB} = 10 V$, $I_E = 0$

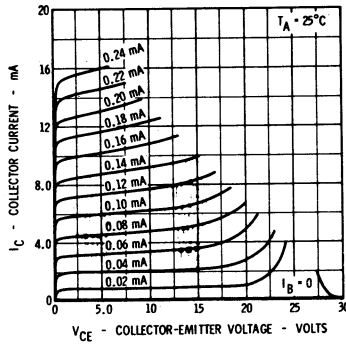
*Planar is a patented Fairchild process.

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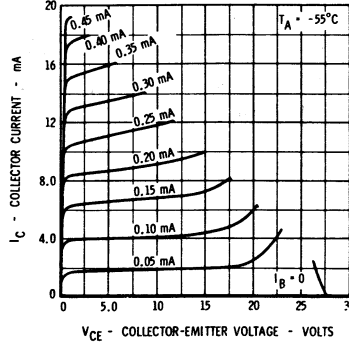
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TYPICAL ELECTRICAL CHARACTERISTICS

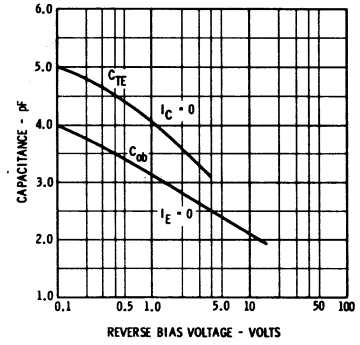
COLLECTOR CHARACTERISTICS*



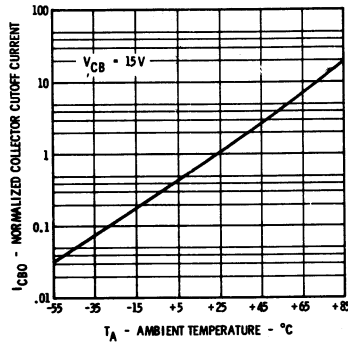
COLLECTOR CHARACTERISTICS*



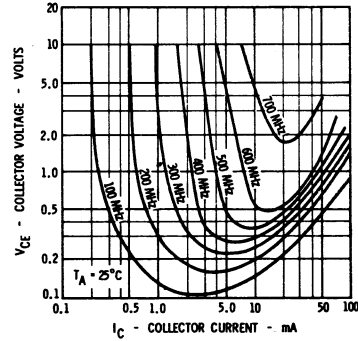
INPUT AND OUTPUT CAPACITANCES VERSUS REVERSE BIAS VOLTAGE



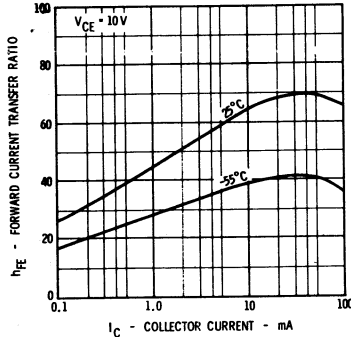
NORMALIZED COLLECTOR CUTOFF CURRENT VERSUS AMBIENT TEMPERATURE



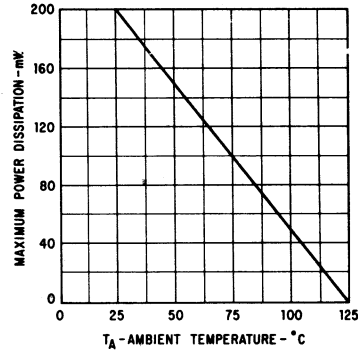
CONTOURS OF CONSTANT GAIN BANDWIDTH PRODUCT (f_T)



DC PULSE CURRENT GAIN VERSUS COLLECTOR CURRENT



MAXIMUM POWER DISSIPATION VERSUS TEMPERATURE



* Single family characteristics on Transistor Curve Tracer

NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These ratings give a maximum junction temperature of 125°C and junction-to-case thermal resistance of 200°C/Watt (derating factor of 5.0 mW/°C); junction-to-ambient thermal resistance of 500°C/Watt (derating factor of 2.0 mW/°C).
- (3) Rating refers to a high-current point where collector-to-emitter voltage is lowest.
- (4) Pulse Conditions: length = 300 μs ; duty cycle ≤ 1%.

2N3565

NPN HIGH GAIN

DIFFUSED SILICON PLANAR*TRANSISTOR

The 2N3565 is a very high beta NPN silicon PLANAR* transistor suited for high gain audio pre-amplifier stages and direct coupled circuits. It also features the solid package designed to give maximum mechanical support to the transistor chip. This is similar to the SE 4002.

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures

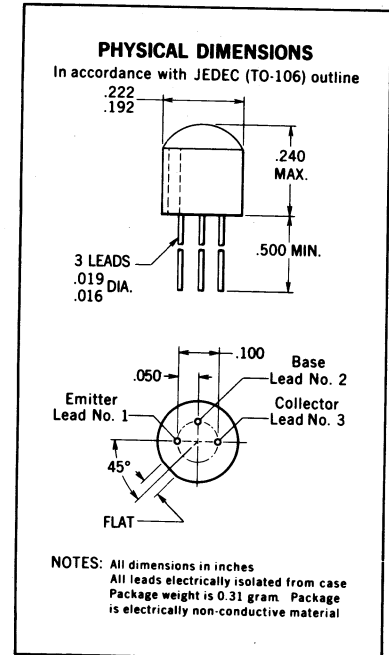
Operating Junction Temperature	+125°C Maximum
Storage Temperature	-55°C to +125°C
Soldering Temperature (10 sec. time limit)	+260°C Maximum

Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature (Note 2)	0.5 Watt
at 65°C Case Temperature (Note 2)	0.3 Watt
at 25°C Ambient Temperature (Note 2)	0.2 Watt

Maximum Voltages

V_{CBO}	Collector to Base Voltage	30 Volts*
V_{CEO}	Collector to Emitter Voltage (Note 3)	25 Volts
V_{EBO}	Emitter to Base Voltage	6.0 Volts



* Planar is a patented Fairchild process.

ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

Symbol	Characteristic	Min.	Max.	Units	Test Conditions
h_{FE}	DC Current Gain	150	600		$I_C = 1.0 \text{ mA}$, $V_{CE} = 10 \text{ V}$
h_{FE}	DC Current Gain	70			$I_C = 100 \mu\text{A}$, $V_{CE} = 10 \text{ V}$
h_{fe}	High Frequency Current Gain ($f = 20 \text{ MHz}$)	2.0			$I_C = 1.0 \text{ mA}$, $V_{CE} = 5.0 \text{ V}$
$V_{CE(sat)}$	Collector Saturation Voltage		0.35	Volts	$I_C = 1.0 \text{ mA}$, $I_B = 0.1 \text{ mA}$
I_{CBO}	Collector Cutoff Current		50	nA	$I_E = 0$, $V_{CB} = 25 \text{ V}$
$I_{CBO(65^\circ\text{C})}$	Collector Cutoff Current		3.0	μA	$I_E = 0$, $V_{CB} = 25 \text{ V}$
C_{obo}	Open Circuit Output Capacitance		4.0	pF	$I_E = 0$, $V_{CB} = 5.0 \text{ V}$
BV_{CBO}	Collector to Base Breakdown Voltage	30		Volts	$I_E = 0$, $I_C = 100 \mu\text{A}$
$V_{CEO(sust)}$	Collector to Emitter Sustaining Voltage (Note 3)	25		Volts	$I_B = 0$, $I_C = 2.0 \text{ mA}$
BV_{EBO}	Emitter to Base Breakdown Voltage	6.0		Volts	$I_C = 0$, $I_E = 10 \mu\text{A}$

NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These ratings give a maximum junction temperature of 125°C and junction-to-case thermal resistance of 200°C/Watt (derating factor of 5.0 mW/°C); junction-to-ambient thermal resistance of 500°C/Watt (derating factor of 2.0 mW/°C).
- Rating refers to a high-current point where collector-to-emitter voltage is lowest.

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FAIRCHILD TRANSISTOR 2N3565

SMALL SIGNAL CHARACTERISTICS (f=1kHz, TA=25°C)

Symbol	Characteristic	Min.	Typ.	Max.	Units		
h_{ie}	Input Resistance	2.0	7.5	20	kohms	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{oe}	Output Conductance		11	35	μmhos	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{re}	Voltage Feedback Ratio		300		$\times 10^{-6}$	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{fe}	Small Signal Current Gain	120	280	750		$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{ib}	Input Resistance		27		Ohms	$I_C = 1.0 \text{ mA}$	$V_{CB} = 5.0 \text{ V}$

2N3566

NPN HIGH GAIN TYPE

DIFFUSED SILICON PLANAR TRANSISTOR

GENERAL DESCRIPTION - The 2N3566 is an NPN Silicon Planar Transistor designed for use in applications requiring very high gain. It is suitable for medium power output driver and low power output circuits. This device is encased in a solid package designed to give maximum mechanical support to the transistor chip. This device is similar to the SE 6002.

ABSOLUTE MAXIMUM RATINGS (Note 1)

Maximum Temperatures

Storage Temperature	-55°C to +125°C
Operating Junction Temperature	+125°C Maximum
Lead Temperature (Soldering, 10 sec. time limit)	+260°C Maximum

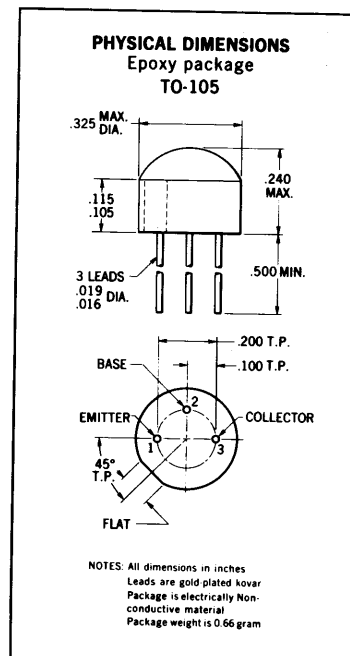
Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature	(Notes 2 and 3)	0.8 Watt
at 75°C Case Temperature	(Notes 2 and 3)	0.4 Watt
at 25°C Ambient Temperature	(Notes 2 and 3)	0.3 Watt

Maximum Voltage

V_{CBO}	Collector to Base Voltage	40 Volts
V_{CEO}	Collector to Emitter Voltage	30 Volts
V_{EBO}	Emitter to Base Voltage	5.0 Volts

(Note 4)



ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Conditions
h_{FE}	DC Pulse Current Gain (Note 5)	150	400	600		$I_C = 10 \text{ mA}$ $V_{CE} = 10 \text{ V}$
h_{FE}	DC Current Gain	80	325			$I_C = 2.0 \text{ mA}$ $V_{CE} = 10 \text{ V}$
V_{BE}	Base-Emitter Voltage (pulsed, see Note 5)		0.87	0.9	Volts	$I_C = 100 \text{ mA}$ $V_{CE} = 1.0 \text{ V}$
$V_{CE(sat)}$	Collector Saturation Voltage (pulsed, see Note 5)		0.9	1.0	Volts	$I_C = 100 \text{ mA}$ $I_B = 10 \text{ mA}$
h_{fe}	High Frequency Current Gain ($f = 20 \text{ Mc}$)	2.0				$I_C = 30 \text{ mA}$ $V_{CE} = 10 \text{ V}$
C_{obo}	Open Circuit Output Capacitance		13	25	pf	$I_E = 0$ $V_{CB} = 10 \text{ V}$
I_{CBO}	Collector Cutoff Current			50	nA	$I_E = 0$ $V_{CB} = 20 \text{ V}$
$I_{CBO(75^\circ C)}$	Collector Cutoff Current			5.0	μA	$I_E = 0$ $V_{CB} = 20 \text{ V}$
BV_{CBO}	Collector to Base Breakdown Voltage	40			Volts	$I_E = 0$ $I_C = 100 \mu A$
$V_{CEO(sust)}$	Collector Emitter Sustaining Voltage (Notes 4 and 5)	30			Volts	$I_C = 30 \text{ mA}$ $I_B = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage	5.0			Volts	$I_C = 0$ $I_E = 100 \mu A$

NOTES:

- These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- These ratings give a maximum junction temperature of 125°C and junction-to-case thermal resistance of 125°C/Watt (derating factor of 8.0 mW/°C); junction-to-ambient thermal resistance of 333°C/Watt (derating factor of 3.0 mW/°C).
- Rating refers to a high-current point where collector-to-emitter voltage is lowest.
- Pulse Conditions: length = 300 μsec ; duty cycle $\leq 1\%$.

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SMALL SIGNAL CHARACTERISTICS (f = 1KC)

Symbol	Characteristic	Typical	Units	Test Conditions		
h_{ie}	Input Resistance	2.5	Kohms	$I_C = 10$ mA	$V_{CE} = 10$ V	
h_{oe}	Output Conductance	120	μ mhos	$I_C = 10$ mA	$V_{CE} = 10$ V	
h_{fe}	Small Signal Current Gain	500		$I_C = 10$ mA	$V_{CE} = 10$ V	
h_{re}	Voltage Feedback Ratio	460	$\times 10^{-6}$	$I_C = 10$ mA	$V_{CE} = 10$ V	

2N3567 • 2N3568

NPN GENERAL PURPOSE TYPES

DIFFUSED SILICON PLANAR* EPITAXIAL TRANSISTORS

The 2N3567 and 2N3568 are NPN silicon PLANAR* epitaxial transistors designed primarily for amplifier and switching applications over a wide range of voltage and current. These devices feature a useful beta range to 500 mA and low saturation voltage. High collector-to-emitter voltage allows operation to 60 volts for the 2N3568 and 40 volts for the 2N3567.

ABSOLUTE MAXIMUM RATINGS [Note 1]

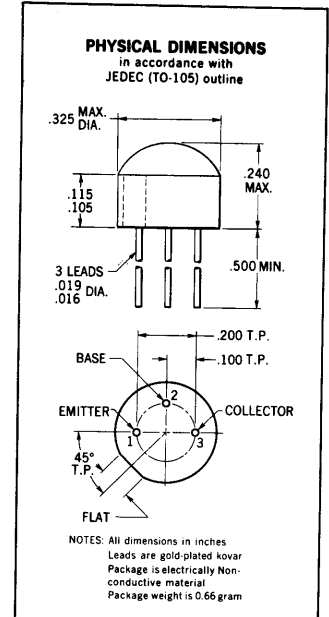
Maximum Temperatures

Storage Temperature	-55°C to +125°C
Operating Junction Temperature	+125°C Maximum
Lead Temperature (Soldering, 10 sec. time limit)	+260°C Maximum

Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature (Notes 2 & 3)	0.8 Watt
at 25°C Ambient Temperature (Notes 2 & 3)	0.3 Watt

Maximum Voltages	2N3567	2N3568
V_{CBO} Collector to Base Voltage	80 Volts	80 Volts
V_{CEO} Collector to Emitter Voltage (Note 4)	40 Volts	60 Volts
V_{EBO} Emitter to Base Voltage	5.0 Volts	5.0 Volts



ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

Symbol	Characteristic		2N3567			2N3568			Units	Test Conditions
			Min.	Typ.	Max.	Min.	Typ.	Max.		
h_{FE}	DC Pulse Current Gain	(Note 5)	40	80	120	40	80	120	$I_C = 150 \text{ mA}$	$V_{CE} = 1.0 \text{ V}$
h_{FE}	DC Pulse Current Gain	(Note 5)	40			40			$I_C = 30 \text{ mA}$	$V_{CE} = 1.0 \text{ V}$
$V_{CE(sat)}$	Collector Saturation Voltage (pulsed, see note 5)		0.15	0.25		0.15	0.25		Volts	$I_C = 150 \text{ mA}$ $I_B = 15 \text{ mA}$
$V_{BE(sat)}$	Base Saturation Voltage (pulsed, see note 5)		0.9	1.1		0.9	1.1		Volts	$I_C = 150 \text{ mA}$ $I_B = 15 \text{ mA}$
h_{fe}	High Frequency Current Gain (f = 20 MHz)		3.0			3.0			$I_C = 50 \text{ mA}$	$V_{CE} = 10 \text{ V}$
C_{obo}	Open Circuit Output Capacitance		13	20		13	20		pF	$I_E = 0$ $V_{CB} = 10 \text{ V}$
C_{ibo}	Open Circuit Input Capacitance		63	80		63	80		pF	$I_C = 0$ $V_{EB} = 0.5 \text{ V}$
I_{CBO}	Collector Cutoff Current				50			50	nA	$I_E = 0$ $V_{CB} = 40 \text{ V}$
$I_{CBO(75^\circ C)}$	Collector Cutoff Current				5.0			5.0	μA	$I_E = 0$ $V_{CB} = 40 \text{ V}$
I_{EBO}	Emitter Cutoff Current				25			25	nA	$I_C = 0$ $V_{EB} = 4.0 \text{ V}$
BV_{CBO}	Collector to Base Breakdown Voltage		80			80			Volts	$I_E = 0$ $I_C = 100 \mu A$
$V_{CEO(sust)}$	Collector to Emitter Sustaining Voltage (Notes 4 and 5)		40			60			Volts	$I_C = 30 \text{ mA}$ (pulsed) $I_B = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage		5.0			5.0			Volts	$I_C = 0$ $I_E = 10 \mu A$

* Planar is a patented Fairchild process.

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SMALL SIGNAL CHARACTERISTICS (f=1.0 kHz)

Symbol	Characteristic	Typical	Units	Test Conditions	
h_{ie}	Input Resistance	1800	Ohms	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{oe}	Output Conductance	8.0	μmhos	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{re}	Voltage Feedback Ratio	2.1	$\times 10^{-4}$	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{fe}	Small Signal Current Gain	60		$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$

NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- (3) These ratings give a maximum junction temperature of 125°C and junction-to-case thermal resistance of 125°C/Watt (derating factor of 8.0 mW/°C; junction-to-ambient thermal resistance of 333°C/Watt (derating factor of 3.0 mW/°C).
- (4) Rating refers to a high-current point where collector-to-emitter voltage is lowest. For more information send for Fairchild Publication APP-4/2.
- (5) Pulse Conditions: length = 300 μs ; duty cycle $\leq 1\%$.

2N3569

NPN GENERAL PURPOSE TYPE

DIFFUSED SILICON PLANAR EPITAXIAL TRANSISTOR

The 2N3569 is an NPN silicon PLANAR epitaxial transistor designed primarily for amplifier and switching applications over a wide range of voltage and current. This device features a useful beta range to 500 mA and low saturation voltage. High collector-to-emitter voltage allows operation to 40 volts.

ABSOLUTE MAXIMUM RATINGS [Note 1]

Maximum Temperatures

Storage Temperature

-55°C to +125°C

Operating Junction Temperature

+125°C Maximum

Lead Temperature (Soldering, 10 sec time limit)

+260°C Maximum

Maximum Power Dissipation

Total Dissipation at 25°C Case Temperature

(Notes 2 and 3)

0.8 Watt

at 25°C Free Air Temperature

(Notes 2 and 3)

0.3 Watt

Maximum Voltages

V_{CBO} Collector to Base Voltage

80 Volts

V_{CEO} Collector to Emitter Voltage

(Note 4)

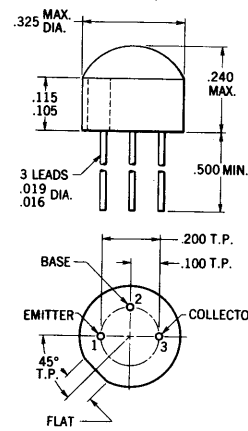
40 Volts

V_{EBO} Emitter to Base Voltage

5.0 Volts

PHYSICAL DIMENSIONS

Epoxy package
TO-105



NOTES: All dimensions in inches
Leads are gold-plated kovar
Package is electrically Non-conductive material
Package weight is 0.66 gram

ELECTRICAL CHARACTERISTICS (25°C Free Air Temperature unless otherwise noted)

Symbol	Characteristic	Min.	Typ.	Max.	Units	Test Conditions
h_{FE}	DC Pulse Current Gain	(Note 5)	100	150	300	$I_C = 150 \text{ mA}$ $V_{CE} = 1.0 \text{ V}$
h_{FE}	DC Pulse Current Gain	(Note 5)	100			$I_C = 30 \text{ mA}$ $V_{CE} = 1.0 \text{ V}$
$V_{CE(sat)}$	Collector Saturation Voltage (pulsed, see note 5)		0.1	0.25	Volts	$I_C = 150 \text{ mA}$ $I_B = 15 \text{ mA}$
$V_{BE(sat)}$	Base Saturation Voltage (pulsed, see note 5)		0.85	1.1	Volts	$I_C = 150 \text{ mA}$ $I_B = 15 \text{ mA}$
h_{fe}	High Frequency Current Gain ($f = 20 \text{ Mc}$)		3.0			$I_C = 50 \text{ mA}$ $V_{CE} = 10 \text{ V}$
C_{obo}	Common Base Open Circuit Output Capacitance		18	20	pf	$I_E = 0$ $V_{CB} = 10 \text{ V}$
C_{ibo}	Common Base Open Circuit Input Capacitance		44	80	pf	$I_C = 0$ $V_{EB} = 0.5 \text{ V}$
I_{CBO}	Collector Cutoff Current			50	nA	$I_E = 0$ $V_{CB} = 40 \text{ V}$
$I_{CBO(75^\circ\text{C})}$	Collector Cutoff Current			5.0	μA	$I_E = 0$ $V_{CB} = 40 \text{ V}$
I_{EBO}	Emitter Cutoff Current			25	nA	$I_C = 0$ $V_{EB} = 4.0 \text{ V}$
BV_{CBO}	Collector to Base Breakdown Voltage		80		Volts	$I_C = 100 \text{ }\mu\text{A}$ $I_E = 0$
$V_{CEO(sust)}$	Collector to Emitter Sustaining Voltage (Notes 4 and 5)		40		Volts	$I_C = 30 \text{ mA}$ (pulsed) $I_B = 0$
BV_{EBO}	Emitter to Base Breakdown Voltage		5.0		Volts	$I_E = 10 \text{ }\mu\text{A}$ $I_C = 0$

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FAIRCHILD TRANSISTOR 2N3569

SMALL SIGNAL CHARACTERISTICS (f=1.0KC)

Symbol	Characteristic	Typical	Units	Test Conditions	
h_{ie}	Input Resistance	3800	Ohms	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{oe}	Output Conductance	19.2	μmhos	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{re}	Voltage Feedback Ratio	5.6	$\times 10^{-4}$	$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$
h_{fe}	Small Signal Current Gain	130		$I_C = 1.0 \text{ mA}$	$V_{CE} = 5.0 \text{ V}$

NOTES:

- (1) These ratings are limiting values above which the serviceability of any individual semiconductor device may be impaired.
- (2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.
- (3) These ratings give a maximum junction temperature of 125°C and junction-to-case thermal resistance of 125°C/Watt (derating factor of 8.0 mW/°C; junction-to-ambient thermal resistance of 333°C/Watt (derating factor of 3.0 mW/°C).
- (4) Rating refers to a high-current point where collector-to-emitter voltage is lowest.
- (5) Pulse Conditions: length = 300 μsec ; duty cycle $\leq 1\%$.